

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/606,223	TANAKA ET AL.	
Examiner		Art Unit		Page 1 of 1
VIJAY SHANKAR		2673		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,510,805	04-1996	Lee, Sywe N.	345/58
	B	US-5,648,790	07-1997	Lee, Sywe N.	345/58
	C	US-6,448,718	09-2002	Battersby, Stephen J.	315/169.3
	D	US-6,882,103	04-2005	Kim et al.	313/504
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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